Infineon Technologies - CY8C3246AXA-137 Datasheet

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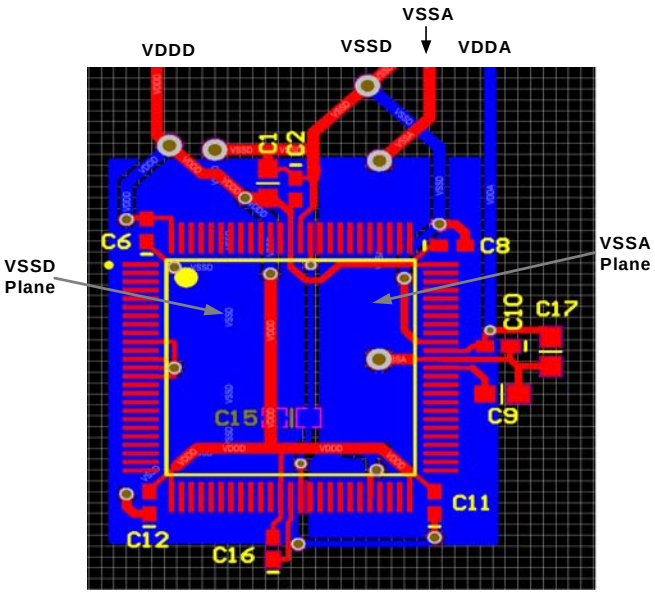
Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	8051
Core Size	8-Bit
Speed	50MHz
Connectivity	EBI/EMI, I²C, LINbus, SPI, UART/USART
Peripherals	CapSense, DMA, POR, PWM, WDT
Number of I/O	62
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x12b; D/A 1x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3246axa-137

Figure 2-8. Example PCB Layout for 100-pin TQFP Part for Optimal Analog Performance



3. Pin Descriptions

IDAC0

Low resistance output pin for high current DAC (IDAC).

Extref0, Extref1

External reference input to the analog system.

GPIO

General purpose I/O pin provides interfaces to the CPU, digital peripherals, analog peripherals, interrupts, LCD segment drive, and CapSense.

I2C0: SCL, I2C1: SCL

I^2C SCL line providing wake from sleep on an address match. Any I/O pin can be used for I^2C SCL if wake from sleep is not required.

I2C0: SDA, I2C1: SDA

I^2C SDA line providing wake from sleep on an address match. Any I/O pin can be used for I^2C SDA if wake from sleep is not required.

Ind

Inductor connection to boost pump.

kHz XTAL: Xo, kHz XTAL: Xi

32.768-kHz crystal oscillator pin.

MHz XTAL: Xo, MHz XTAL: Xi

4- to 25- MHz crystal oscillator pin.

nTRST

Optional JTAG test reset programming and debug port connection to reset the JTAG connection.

SIO

Special I/O provides interfaces to the CPU, digital peripherals and interrupts with a programmable high threshold voltage, analog comparator, high sink current, and high impedance state when the device is unpowered.

SWDCK

Serial wire debug clock programming and debug port connection.

SWDIO

Serial wire debug input and output programming and debug port connection.

SWV.

Single wire viewer debug output.

TCK

JTAG test clock programming and debug port connection.

TDI

JTAG test data in programming and debug port connection.

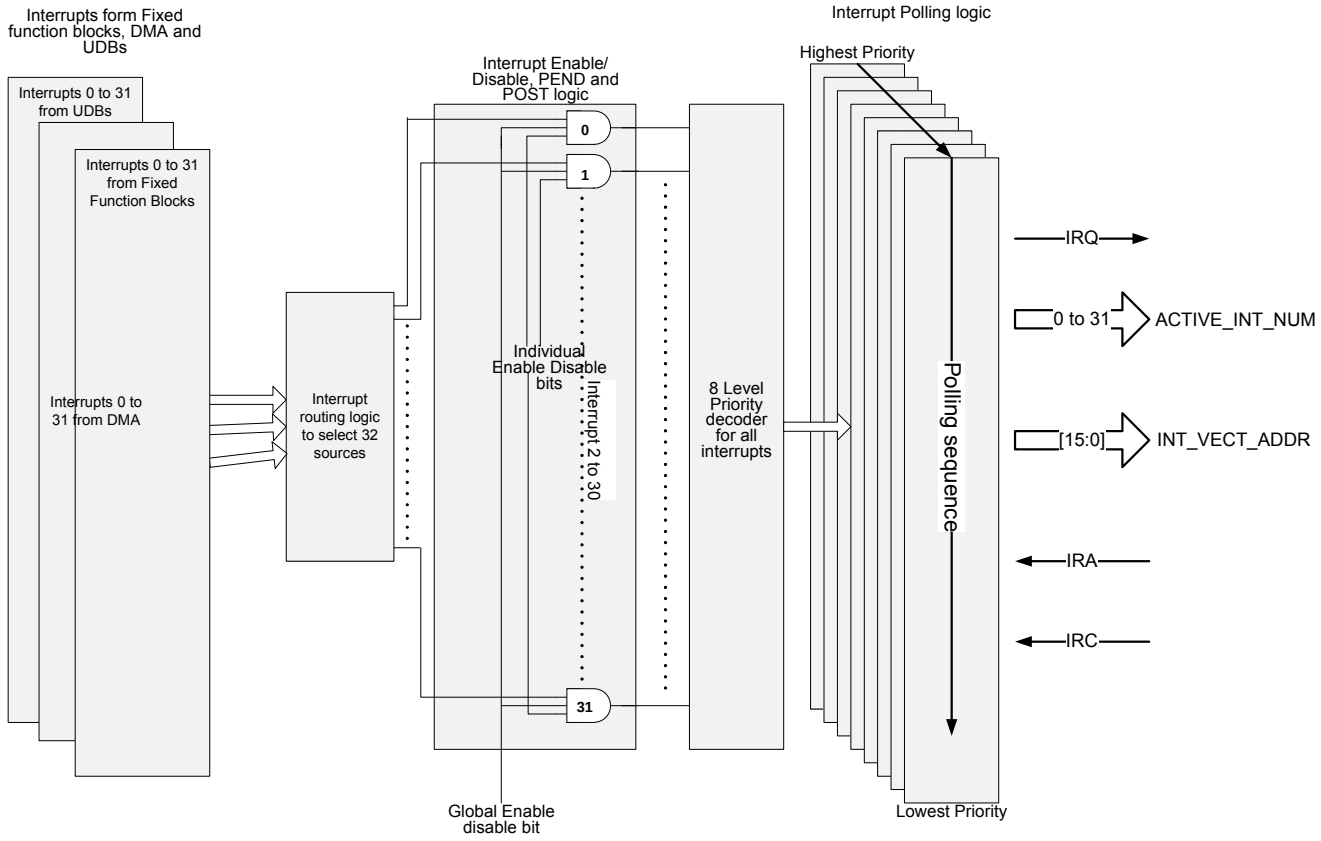
TDO

JTAG test data out programming and debug port connection.

TMS

JTAG test mode select programming and debug port connection.

Figure 4-3. Interrupt Structure



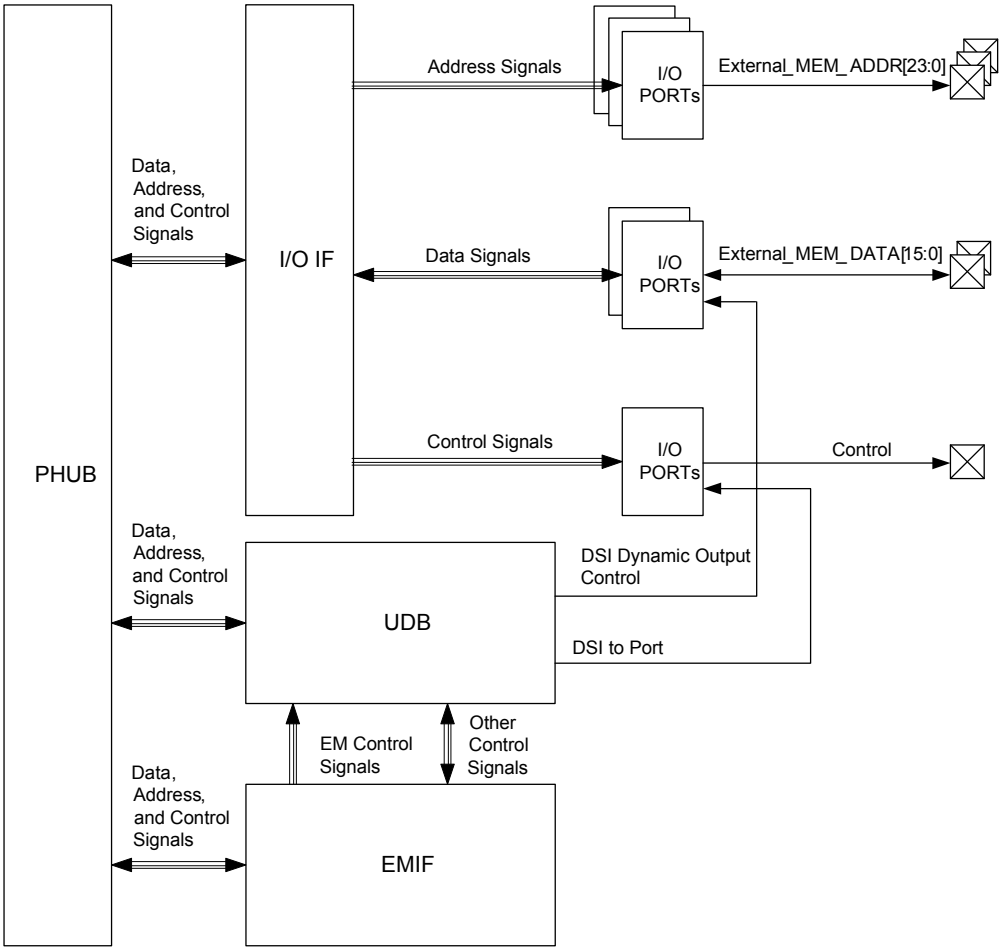
5.6 External Memory Interface

CY8C32 provides an external memory interface (EMIF) for connecting to external memory devices. The connection allows read and write accesses to external memories. The EMIF operates in conjunction with UDBs, I/O ports, and other hardware to generate external memory address and control signals. At 33 MHz, each memory access cycle takes four bus clock cycles.

Figure 5-1 is the EMIF block diagram. The EMIF supports synchronous and asynchronous memories. The CY8C32 supports only one type of external memory device at a time.

External memory can be accessed via the 8051 xdata space; up to 24 address bits can be used. See "xdata Space" section on page 28. The memory can be 8 or 16 bits wide.

Figure 5-1. EMIF Block Diagram



5.7 Memory Map

The CY8C32 8051 memory map is very similar to the MCS-51 memory map.

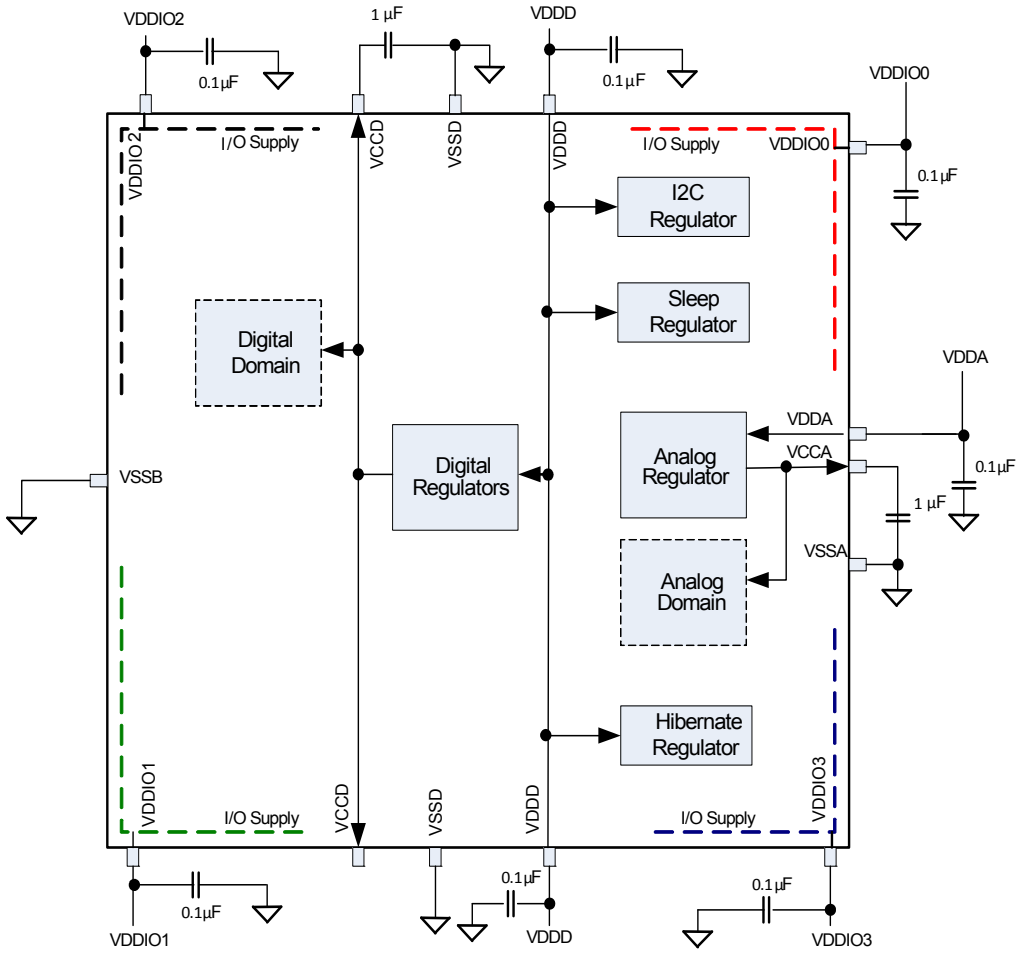
5.7.1 Code Space

The CY8C32 8051 code space is 64 KB. Only main flash exists in this space. See the "Flash Program Memory" section on page 24.

5.7.2 Internal Data Space

The CY8C32 8051 internal data space is 384 bytes, compressed within a 256-byte space. This space consists of 256 bytes of RAM (in addition to the SRAM mentioned in Static RAM on page 24) and a 128-byte space for Special Function Registers (SFRs). See Figure 5-2. The lowest 32 bytes are used for 4 banks of registers R0-R7. The next 16 bytes are bit-addressable.

Figure 6-4. PSoC Power System



Notes

- The two VCCD pins must be connected together with as short a trace as possible. A trace under the device is recommended, as shown in Figure 2-8 on page 12.
- It is good practice to check the datasheets for your bypass capacitors, specifically the working voltage and the DC bias specifications. With some capacitors, the actual capacitance can decrease considerably when the DC bias (VDDX or VCCX in Figure 6-4) is a significant percentage of the rated working voltage.
- You can power the device in internally regulated mode, where the voltage applied to the VDDx pins is as high as 5.5 V, and the internal regulators provide the core voltages. **In this mode, do not apply power to the VCCx pins, and do not tie the VDDx pins to the VCCx pins.**
- You can also power the device in externally regulated mode, that is, by directly powering the VCCD and VCCA pins. In this configuration, the VDDD pins should be shorted to the VCCD pins and the VDDA pin should be shorted to the VCCA pin. The allowed supply range in this configuration is 1.71 V to 1.89 V. After power up in this configuration, the internal regulators are on by default, and should be disabled to reduce power consumption.

The term **device reset** indicates that the processor as well as analog and digital peripherals and registers are reset.

A reset status register shows some of the resets or power voltage monitoring interrupts. The program may examine this register to detect and report certain exception conditions. This register is cleared after a power-on reset. For details see the Technical Reference Manual.

6.3.1 Reset Sources

6.3.1.1 Power Voltage Level Monitors

- IPOR – Initial Power-on Reset

  At initial power on, IPOR monitors the power voltages VDDD, VDDA, VCCD, and VCCA. The trip level is not precise. It is set to approximately 1 volt, which is below the lowest specified operating voltage but high enough for the internal circuits to be reset and to hold their reset state. The monitor generates a reset pulse that is at least 150 ns wide. It may be much wider if one or more of the voltages ramps up slowly.

  After boot, the IPOR circuit is disabled and voltage supervision is handed off to the precise low-voltage reset (PRES) circuit.

- PRES – Precise Low Voltage Reset

  This circuit monitors the outputs of the analog and digital internal regulators after power up. The regulator outputs are compared to a precise reference voltage. The response to a PRES trip is identical to an IPOR reset.

  In normal operating mode, the program cannot disable the digital PRES circuit. The analog regulator can be disabled, which also disables the analog portion of the PRES. The PRES circuit is disabled automatically during sleep and hibernate modes, with one exception: During sleep mode the regulators are periodically activated (buzzed) to provide supervisory services and to reduce wakeup time. At these times the PRES circuit is also buzzed to allow periodic voltage monitoring.

- ALVI, DLVI, AHVI – Analog/Digital Low Voltage Interrupt, Analog High Voltage Interrupt

  Interrupt circuits are available to detect when VDDA and VDDD go outside a voltage range. For AHVI, VDDA is compared to a fixed trip level. For ALVI and DLVI, VDDA and VDDD are compared to trip levels that are programmable, as listed in Table 6-5. ALVI and DLVI can also be configured to generate a device reset instead of an interrupt.

Table 6-5. Analog/Digital Low Voltage Interrupt, Analog High Voltage Interrupt

Interrupt	Supply	Normal Voltage Range	Available Trip Settings
DLVI	VDDD	1.71 V – 5.5 V	1.70 V – 5.45 V in 250 mV increments
ALVI	VDDA	1.71 V – 5.5 V	1.70 V – 5.45 V in 250 mV increments
AHVI	VDDA	1.71 V – 5.5 V	5.75 V

The monitors are disabled until after IPOR. During sleep mode these circuits are periodically activated (buzzed). If an interrupt occurs during buzzing then the system first enters its wake up sequence. The interrupt is then recognized and may be serviced.

The buzz frequency is adjustable, and should be set to be less than the minimum time that any voltage is expected to be out of range. For details on how to adjust the buzz frequency, see the TRM.

6.3.1.2 Other Reset Sources

- XRES – External Reset

  PSoC 3 has either a single GPIO pin that is configured as an external reset or a dedicated XRES pin. Either the dedicated XRES pin or the GPIO pin, if configured, holds the part in reset while held active (low). The response to an XRES is the same as to an IPOR reset.

  After XRES has been deasserted, at least 10 µs must elapse before it can be reasserted.

  The external reset is active low. It includes an internal pull-up resistor. XRES is active during sleep and hibernate modes.

- SRES – Software Reset

  A reset can be commanded under program control by setting a bit in the software reset register. This is done either directly by the program or indirectly by DMA access. The response to a SRES is the same as after an IPOR reset.

  Another register bit exists to disable this function.

- WRES – Watchdog Timer Reset

  The watchdog reset detects when the software program is no longer being executed correctly. To indicate to the watchdog timer that it is running correctly, the program must periodically reset the timer. If the timer is not reset before a user-specified amount of time, then a reset is generated.

  Note IPOR disables the watchdog function. The program must enable the watchdog function at an appropriate point in the code by setting a register bit. When this bit is set, it cannot be cleared again except by an IPOR power-on reset event.

6.4 I/O System and Routing

PSoC I/Os are extremely flexible. Every GPIO has analog and digital I/O capability. All I/Os have a large number of drive modes, which are set at POR. PSoC also provides up to four individual I/O voltage domains through the VDDIO pins.

There are two types of I/O pins on every device; those with USB provide a third type. Both GPIO and Special I/O (SIO) provide similar digital functionality. The primary differences are their analog capability and drive strength. Devices that include USB also provide two USBIO pins that support specific USB functionality as well as limited GPIO capability.

All I/O pins are available for use as digital inputs and outputs for both the CPU and digital peripherals. In addition, all I/O pins can generate an interrupt. The flexible and advanced capabilities of the PSoC I/O, combined with any signal to any pin routability, greatly simplify circuit design and board layout. All GPIO pins can be used for analog input, CapSense, and LCD segment drive, while SIO pins are used for voltages in excess of VDDA and for programmable output voltages.

- Features supported by both GPIO and SIO:
  - User programmable port reset state
  - Separate I/O supplies and voltages for up to four groups of I/O
  - Digital peripherals use DSI to connect the pins

Independent of the ALU operation, these functions are available:

- Shift left
- Shift right
- Nibble swap
- Bitwise OR mask

7.2.2.3 Conditionals

Each datapath has two compares, with bit masking options. Compare operands include the two accumulators and the two data registers in a variety of configurations. Other conditions include zero detect, all ones detect, and overflow. These conditions are the primary datapath outputs, a selection of which can be driven out to the UDB routing matrix. Conditional computation can use the built in chaining to neighboring UDBs to operate on wider data widths without the need to use routing resources.

7.2.2.4 Variable MSB

The most significant bit of an arithmetic and shift function can be programmatically specified. This supports variable width CRC and PRS functions, and in conjunction with ALU output masking, can implement arbitrary width timers, counters and shift blocks.

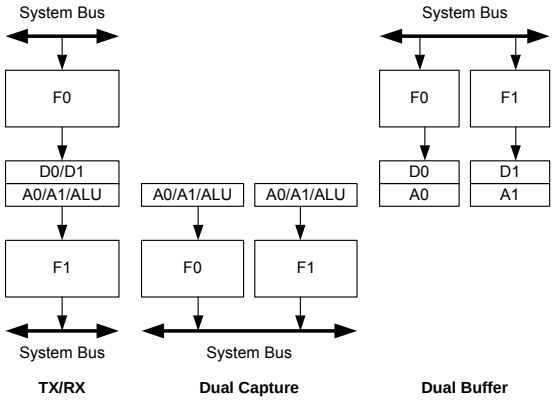
7.2.2.5 Built in CRC/PRS

The datapath has built in support for single cycle Cyclic Redundancy Check (CRC) computation and Pseudo Random Sequence (PRS) generation of arbitrary width and arbitrary polynomial. CRC/PRS functions longer than 8 bits may be implemented in conjunction with PLD logic, or built in chaining may be use to extend the function into neighboring UDBs.

7.2.2.6 Input/Output FIFOs

Each datapath contains two four-byte deep FIFOs, which can be independently configured as an input buffer (system bus writes to the FIFO, datapath internal reads the FIFO), or an output buffer (datapath internal writes to the FIFO, the system bus reads from the FIFO). The FIFOs generate status that are selectable as datapath outputs and can therefore be driven to the routing, to interact with sequencers, interrupts, or DMA.

Figure 7-5. Example FIFO Configurations



7.2.2.7 Chaining

The datapath can be configured to chain conditions and signals such as carries and shift data with neighboring datapaths to create higher precision arithmetic, shift, CRC/PRS functions.

7.2.2.8 Time Multiplexing

In applications that are over sampled, or do not need high clock rates, the single ALU block in the datapath can be efficiently shared with two sets of registers and condition generators. Carry and shift out data from the ALU are registered and can be selected as inputs in subsequent cycles. This provides support for 16-bit functions in one (8-bit) datapath.

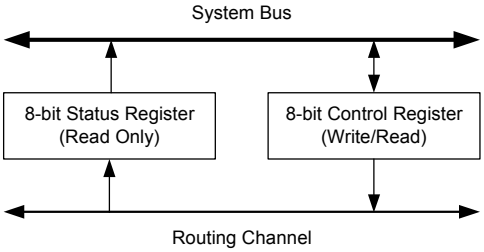
7.2.2.9 Datapath I/O

There are six inputs and six outputs that connect the datapath to the routing matrix. Inputs from the routing provide the configuration for the datapath operation to perform in each cycle, and the serial data inputs. Inputs can be routed from other UDB blocks, other device peripherals, device I/O pins, and so on. The outputs to the routing can be selected from the generated conditions, and the serial data outputs. Outputs can be routed to other UDB blocks, device peripherals, interrupt and DMA controller, I/O pins, and so on.

7.2.3 Status and Control Module

The primary purpose of this circuitry is to coordinate CPU firmware interaction with internal UDB operation.

Figure 7-6. Status and Control Registers

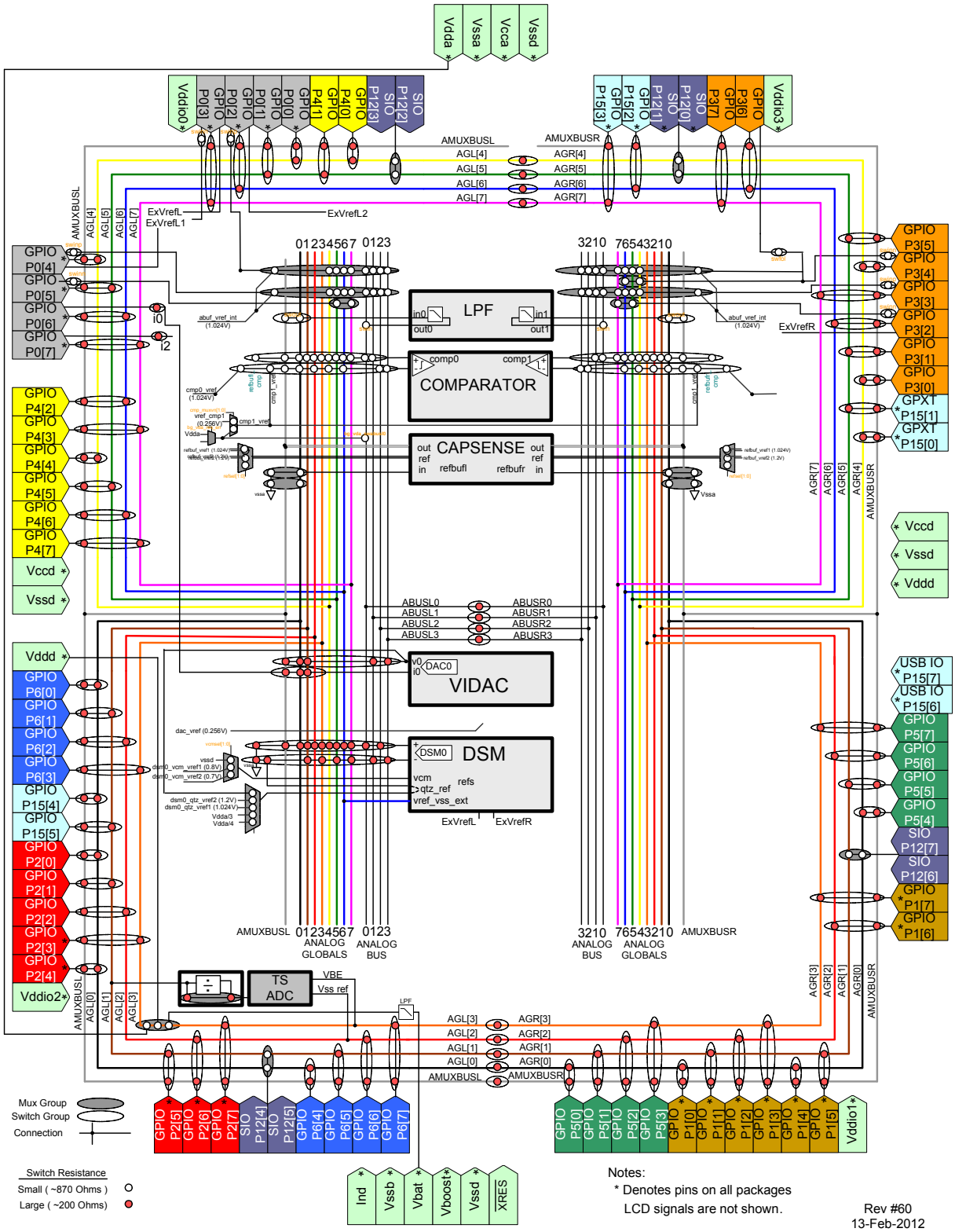


The bits of the control register, which may be written to by the system bus, are used to drive into the routing matrix, and thus provide firmware with the opportunity to control the state of UDB processing. The status register is read-only and it allows internal UDB state to be read out onto the system bus directly from internal routing. This allows firmware to monitor the state of UDB processing. Each bit of these registers has programmable connections to the routing matrix and routing connections are made depending on the requirements of the application.

7.2.3.1 Usage Examples

As an example of control input, a bit in the control register can be allocated as a function enable bit. There are multiple ways to enable a function. In one method the control bit output would be routed to the clock control block in one or more UDBs and serve as a clock enable for the selected UDB blocks. A status example is a case where a PLD or datapath block generated a condition, such as a “compare true” condition that is captured and latched by the status register and then read (and cleared) by CPU firmware.

Figure 8-2. CY8C32 Analog Interconnect



To preserve detail of this figure, this figure is best viewed with a PDF display program or printed on a 11" × 17" paper.

11. Electrical Specifications

Specifications are valid for –40 °C ≤ T_A ≤ 85 °C and T_J ≤ 100 °C, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted. The unique flexibility of the PSoC UDBs and analog blocks enable many functions to be implemented in PSoC Creator components, see the component datasheets for full AC/DC specifications of individual functions. See the "Example Peripherals" section on page 45 for further explanation of PSoC Creator components.

11.1 Absolute Maximum Ratings

Table 11-1. Absolute Maximum Ratings DC Specifications[15]

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{DDA}	Analog supply voltage relative to V_{SSA}		–0.5	–	6	V
V_{DDD}	Digital supply voltage relative to V_{SSD}		–0.5	–	6	V
V_{DDIO}	I/O supply voltage relative to V_{SSD}		–0.5	–	6	V
V_{CCA}	Direct analog core voltage input		–0.5	–	1.95	V
V_{CCD}	Direct digital core voltage input		–0.5	–	1.95	V
V_{SSA}	Analog ground voltage		V_{SSD} –0.5	–	V_{SSD} + 0.5	V
V_{GPIO}[16]	DC input voltage on GPIO	Includes signals sourced by V_{DDA} and routed internal to the pin	V_{SSD} –0.5	–	V_{DDIO} + 0.5	V
V_{SIO}	DC input voltage on SIO	Output disabled	V_{SSD} –0.5	–	7	V
		Output enabled	V_{SSD} –0.5	–	6	V
V_{IND}	Voltage at boost converter input		0.5	–	5.5	V
V_{BAT}	Boost converter supply		V_{SSD} –0.5	–	5.5	V
I_{VDDIO}	Current per V_{DDIO} supply pin		–	–	100	mA
I_{GPIO}	GPIO current		–30	–	41	mA
I_{SIO}	SIO current		–49	–	28	mA
I_{USBIO}	USBIO current		–56	–	59	mA
VEXTREF	ADC external reference inputs	Pins P0[3], P3[2]	–	–	2	V
LU	Latch up current[17]		–140	–	140	mA
ESD_{HBM}	Electrostatic discharge voltage, Human body model	V_{SSA} tied to V_{SSD}	2200	–	–	V
		V_{SSA} not tied to V_{SSD}	750	–	–	V
ESD_{CDM}	Electrostatic discharge voltage, Charge device model		500	–	–	V

Notes
15. Usage above the absolute maximum conditions listed in Table 11-1 may cause permanent damage to the device. Exposure to Absolute Maximum conditions for extended periods of time may affect device reliability. The Maximum Storage Temperature is 150 °C in compliance with JEDEC Standard JESD22-A103, High Temperature Storage Life. When used below Absolute Maximum conditions but above normal operating conditions, the device may not operate to specification.
16. The V_{DDIO} supply voltage must be greater than the maximum voltage on the associated GPIO pins. Maximum voltage on GPIO pin ≤ V_{DDIO} ≤ V_{DDA}.
17. Meets or exceeds JEDEC Spec EIA/JESD78 IC Latch-up Test.

Table 11-2. DC Specifications *(continued)*

Parameter	Description	Conditions		Min	Typ[22]	Max	Units
	Sleep Mode[25]						
	CPU = OFF RTC = ON (= ECO32K ON, in low-power mode) Sleep timer = ON (= ILO ON at 1 kHz)[26] WDT = OFF I^2C Wake = OFF Comparator = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 4.5 V - 5.5 V	T = –40 °C	–	1.1	2.3	µA
			T = 25 °C	–	1.1	2.2	
			T = 85 °C	–	15	30	
		$V_{DD} = V_{DDIO}$ = 2.7 V – 3.6 V	T = –40 °C	–	1	2.2	
			T = 25 °C	–	1	2.1	
			T = 85 °C	–	12	28	
		$V_{DD} = V_{DDIO}$ = 1.71 V – 1.95 V[27]	T = 25 °C	–	2.2	4.2	
	Comparator = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF I^2C Wake = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 2.7 V – 3.6 V[28]	T = 25 °C	–	2.2	2.7	
	I^2C Wake = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF Comparator = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 2.7 V – 3.6 V[28]	T = 25 °C	–	2.2	2.8	
	Hibernate Mode[25]						
	Hibernate mode current All regulators and oscillators off SRAM retention GPIO interrupts are active Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 4.5 V - 5.5 V	T = –40 °C	–	0.2	1.5	µA
			T = 25 °C	–	0.5	1.5	
			T = 85 °C	–	4.1	5.3	
		$V_{DD} = V_{DDIO}$ = 2.7 V – 3.6 V	T = –40 °C	–	0.2	1.5	
			T = 25 °C	–	0.2	1.5	
			T = 85 °C	–	3.2	4.2	
		$V_{DD} = V_{DDIO}$ = 1.71 V – 1.95 V[27]	T = –40 °C	–	0.2	1.5	
			T = 25 °C	–	0.3	1.5	
			T = 85 °C	–	3.3	4.3	
I_{DDAR}	Analog current consumption while device is reset[29]	$V_{DDA} \leq 3.6$ V		–	0.3	0.6	mA
		$V_{DDA} > 3.6$ V		–	1.4	3.3	mA
I_{DDDR}	Digital current consumption while device is reset[29]	$V_{DDD} \leq 3.6$ V		–	1.1	3.1	mA
		$V_{DDD} > 3.6$ V		–	0.7	3.1	mA

11.3.3 Inductive Boost Regulator

Unless otherwise specified, operating conditions are: V_{BAT} = 0.5 V–3.6 V, V_{OUT} = 1.8 V–5.0 V, I_{OUT} = 0 mA–50 mA, L_{BOOST} = 4.7 µH–22 µH, C_{BOOST} = 22 µF || 3 × 1.0 µF || 3 × 0.1 µF, C_{BAT} = 22 µF, I_F = 1.0 A. Unless otherwise specified, all charts and graphs show typical values.

Table 11-6. Inductive Boost Regulator DC Specifications

Parameter	Description	Conditions		Min	Typ	Max	Units
V_{OUT}	Boost output voltage[31]	vsel = 1.8 V in register BOOST_CR0		1.71	1.8	1.89	V
		vsel = 1.9 V in register BOOST_CR0		1.81	1.90	2.00	V
		vsel = 2.0 V in register BOOST_CR0		1.90	2.00	2.10	V
		vsel = 2.4 V in register BOOST_CR0		2.16	2.40	2.64	V
		vsel = 2.7 V in register BOOST_CR0		2.43	2.70	2.97	V
		vsel = 3.0 V in register BOOST_CR0		2.70	3.00	3.30	V
		vsel = 3.3 V in register BOOST_CR0		2.97	3.30	3.63	V
		vsel = 3.6 V in register BOOST_CR0		3.24	3.60	3.96	V
		vsel = 5.0 V in register BOOST_CR0		4.50	5.00	5.50	V
V_{BAT}	Input voltage to boost[32]	I_{OUT} = 0 mA–5 mA	vsel = 1.8 V–2.0 V, T_A = 0 °C–70 °C	0.5	–	0.8	V
		I_{OUT} = 0 mA–15 mA	vsel = 1.8 V–5.0 V[33], T_A = –10 °C–85 °C	1.6	–	3.6	V
		I_{OUT} = 0 mA–25 mA	vsel = 1.8 V–2.7 V, T_A = –10 °C–85 °C	0.8	–	1.6	V
		I_{OUT} = 0 mA–50 mA	vsel = 1.8 V–3.3 V[33], T_A = –40 °C–85 °C	1.8	–	2.5	V
			vsel = 1.8 V–3.3 V[33], T_A = –10 °C–85 °C	1.3	–	2.5	V
			vsel = 2.5 V–5.0 V[33], T_A = –10 °C–85 °C	2.5	–	3.6	V
I_{OUT}	Output current	T_A = 0 °C–70 °C	V_{BAT} = 0.5 V–0.8 V	0	–	5	mA
		T_A = –10 °C–85 °C	V_{BAT} = 1.6 V–3.6 V	0	–	15	mA
			V_{BAT} = 0.8 V–1.6 V	0	–	25	mA
			V_{BAT} = 1.3 V–2.5 V	0	–	50	mA
			V_{BAT} = 2.5 V–3.6 V	0	–	50	mA
		T_A = –40 °C–85 °C	V_{BAT} = 1.8 V–2.5 V	0	–	50	mA
I_{LPK}	Inductor peak current			–	–	700	mA
I_Q	Quiescent current	Boost active mode		–	250	–	µA
		Boost sleep mode, I_{OUT} < 1 µA		–	25	–	µA
Reg_{LOAD}	Load regulation			–	–	10	%
Reg_{LINE}	Line regulation			–	–	10	%

Notes
31. Listed vsel options are characterized. Additional vsel options are valid and guaranteed by design.
32. The boost will start at all valid V_{BAT} conditions including down to V_{BAT} = 0.5 V.
33. If V_{BAT} is greater than or equal to V_{OUT} boost setting, then V_{OUT} will be less than V_{BAT} due to resistive losses in the boost circuit.

Table 11-7. Recommended External Components for Boost Circuit

Parameter	Description	Conditions	Min	Typ	Max	Units
L_{BOOST}	Boost inductor	4.7 µH nominal	3.7	4.7	5.7	µH
		10 µH nominal	8.0	10.0	12.0	µH
		22 µH nominal	17.0	22.0	27.0	µH
C_{BOOST}	Total capacitance sum of V_{DDD}, V_{DDA}, V_{DDIO}[34]		17.0	26.0	31.0	µF
C_{BAT}	Battery filter capacitor		17.0	22.0	27.0	µF
I_F	Schottky diode average forward current		1.0	–	–	A
V_R	Schottky reverse voltage		20.0	–	–	V

Figure 11-8. T_A range over V_{BAT} and V_{OUT}

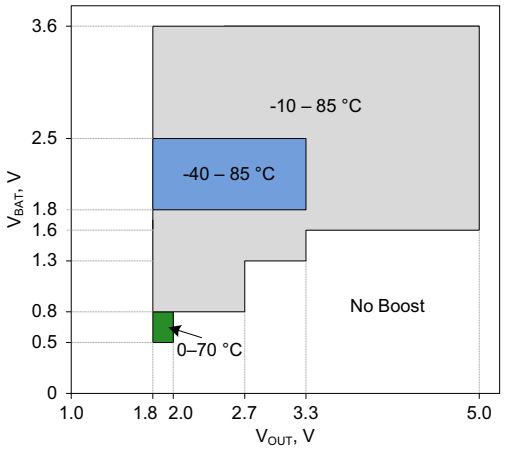


Figure 11-9. I_{OUT} range over V_{BAT} and V_{OUT}

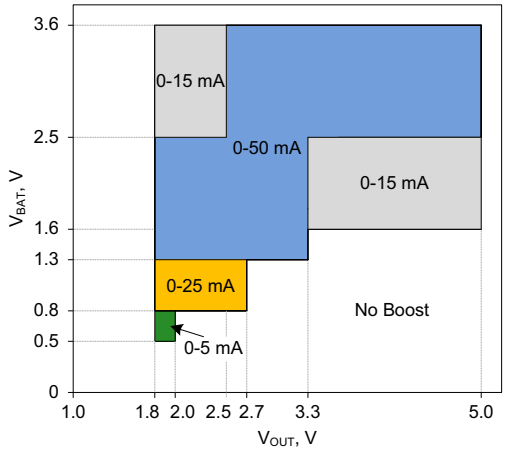
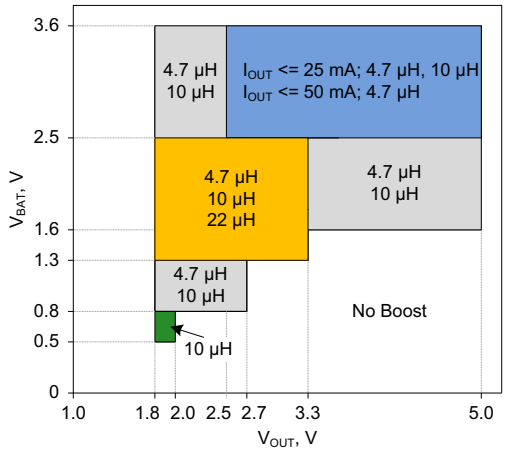


Figure 11-10. L_{BOOST} values over V_{BAT} and V_{OUT}



Note
34. Based on device characterization (Not production tested).

Table 11-13. SIO Comparator Specifications[42]

Parameter	Description	Conditions	Min	Typ	Max	Units
Vos	Offset voltage	V_{DDIO} = 2 V	–	–	68	mV
		V_{DDIO} = 2.7 V	–	–	72	
		V_{DDIO} = 5.5 V	–	–	82	
TCVos	Offset voltage drift with temp		–	–	250	µV/°C
CMRR	Common mode rejection ratio	V_{DDIO} = 2 V	30	–	–	dB
		V_{DDIO} = 2.7 V	35	–	–	
		V_{DDIO} = 5.5 V	40	–	–	
Tresp	Response time		–	–	30	ns

11.4.3 USBIO

For operation in GPIO mode, the standard range for V_{DDD} applies, see Device Level Specifications on page 68.

Table 11-14. USBIO DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Rusbi	USB D+ pull-up resistance	With idle bus	0.900	–	1.575	kΩ
Rusba	USB D+ pull-up resistance	While receiving traffic	1.425	–	3.090	kΩ
Vohusb	Static output high	15 kΩ ±5% to Vss, internal pull-up enabled	2.8	–	3.6	V
Volusb	Static output low	15 kΩ ±5% to Vss, internal pull-up enabled	–	–	0.3	V
Vohgpio	Output voltage high, GPIO mode	I_{OH} = 4 mA, $V_{DDD} \geq$ 3 V	2.4	–	–	V
Volgpio	Output voltage low, GPIO mode	I_{OL} = 4 mA, $V_{DDD} \geq$ 3 V	–	–	0.3	V
Vdi	Differential input sensitivity	|(D+)–(D–)|	–	–	0.2	V
Vcm	Differential input common mode range	–	0.8	–	2.5	V
Vse	Single ended receiver threshold	–	0.8	–	2	V
Rps2	PS/2 pull-up resistance	In PS/2 mode, with PS/2 pull-up enabled	3	–	7	kΩ
Rext	External USB series resistor	In series with each USB pin	21.78 (–1%)	22	22.22 (+1%)	Ω
Zo	USB driver output impedance	Including Rext	28	–	44	Ω
C_{IN}	USB transceiver input capacitance	–	–	–	20	pF
I_{IL}[42]	Input leakage current (absolute value)	25 °C, V_{DDD} = 3.0 V	–	–	2	nA

Note
42. Based on device characterization (Not production tested).

Figure 11-22. USBIO Output High Voltage and Current, GPIO Mode

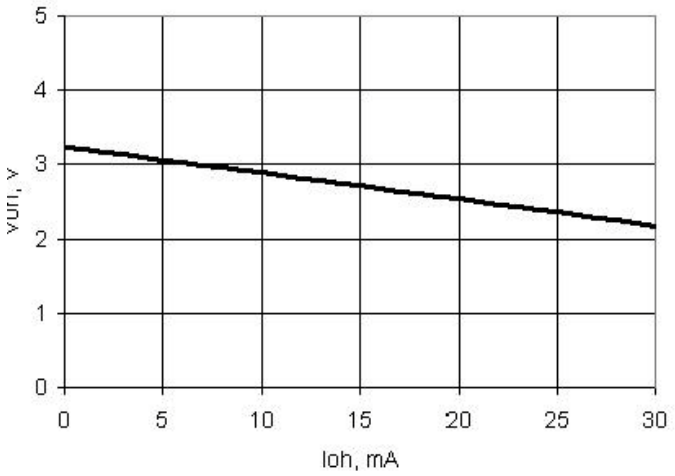


Figure 11-23. USBIO Output Low Voltage and Current, GPIO Mode

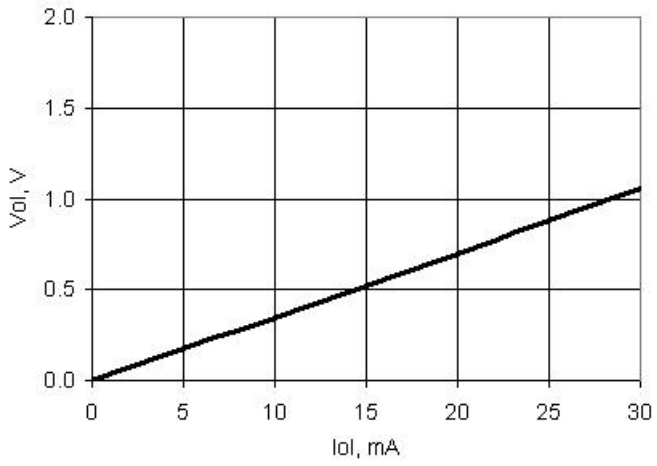


Table 11-15. USBIO AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Tdrate	Full-speed data rate average bit rate		12 – 0.25%	12	12 + 0.25%	MHz
Tjr1	Receiver data jitter tolerance to next transition		–8	–	8	ns
Tjr2	Receiver data jitter tolerance to pair transition		–5	–	5	ns
Tdj1	Driver differential jitter to next transition		–3.5	–	3.5	ns
Tdj2	Driver differential jitter to pair transition		–4	–	4	ns
Tfdeop	Source jitter for differential transition to SE0 transition		–2	–	5	ns
Tfeopt	Source SE0 interval of EOP		160	–	175	ns
Tfeopr	Receiver SE0 interval of EOP		82	–	–	ns
Tfst	Width of SE0 interval during differential transition		–	–	14	ns
Fgpio_out	GPIO mode output operating frequency	3 V ≤ V_{DDD} ≤ 5.5 V	–	–	20	MHz
		V_{DDD} = 1.71 V	–	–	6	MHz
Tr_gpio	Rise time, GPIO mode, 10%/90% V_{DDD}	V_{DDD} > 3 V, 25 pF load	–	–	12	ns
		V_{DDD} = 1.71 V, 25 pF load	–	–	40	ns
Tf_gpio	Fall time, GPIO mode, 90%/10% V_{DDD}	V_{DDD} > 3 V, 25 pF load	–	–	12	ns
		V_{DDD} = 1.71 V, 25 pF load	–	–	40	ns

Figure 11-24. USBIO Output Rise and Fall Times, GPIO Mode,

Figure 11-28. IDAC DNL vs Input Code, Range = 255 µA, Source Mode

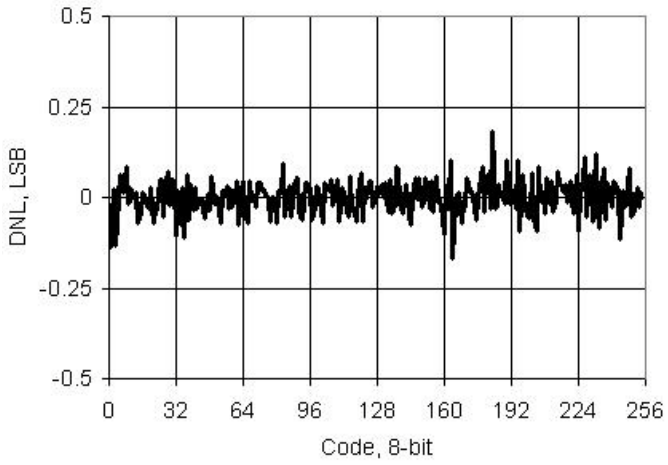


Figure 11-29. IDAC DNL vs Input Code, Range = 255 µA, Sink Mode

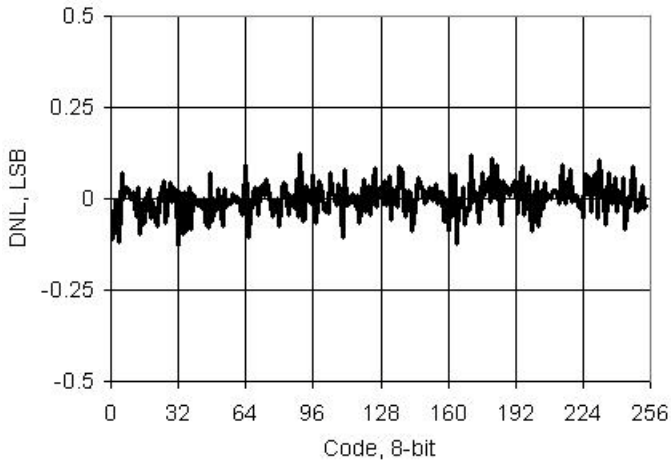


Figure 11-30. IDAC INL vs Temperature, Range = 255 µA, High speed mode

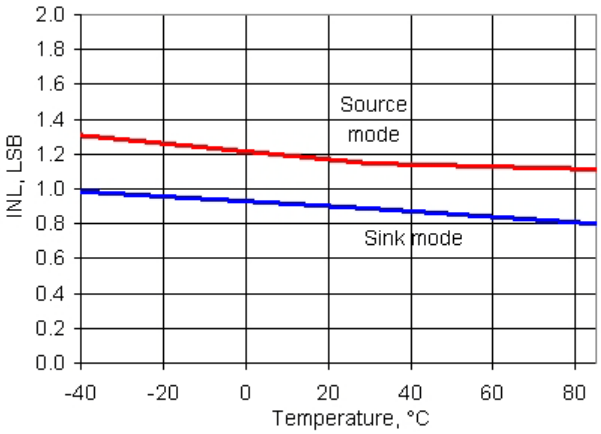
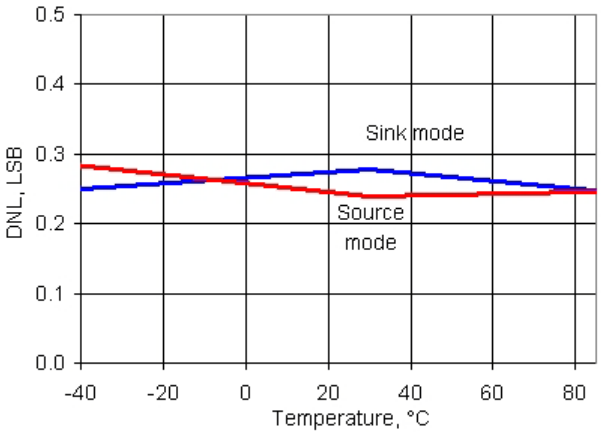


Figure 11-31. IDAC DNL vs Temperature, Range = 255 µA, High speed mode



11.7.5 External Memory Interface

Figure 11-53. Asynchronous Write and Read Cycle Timing, No Wait States

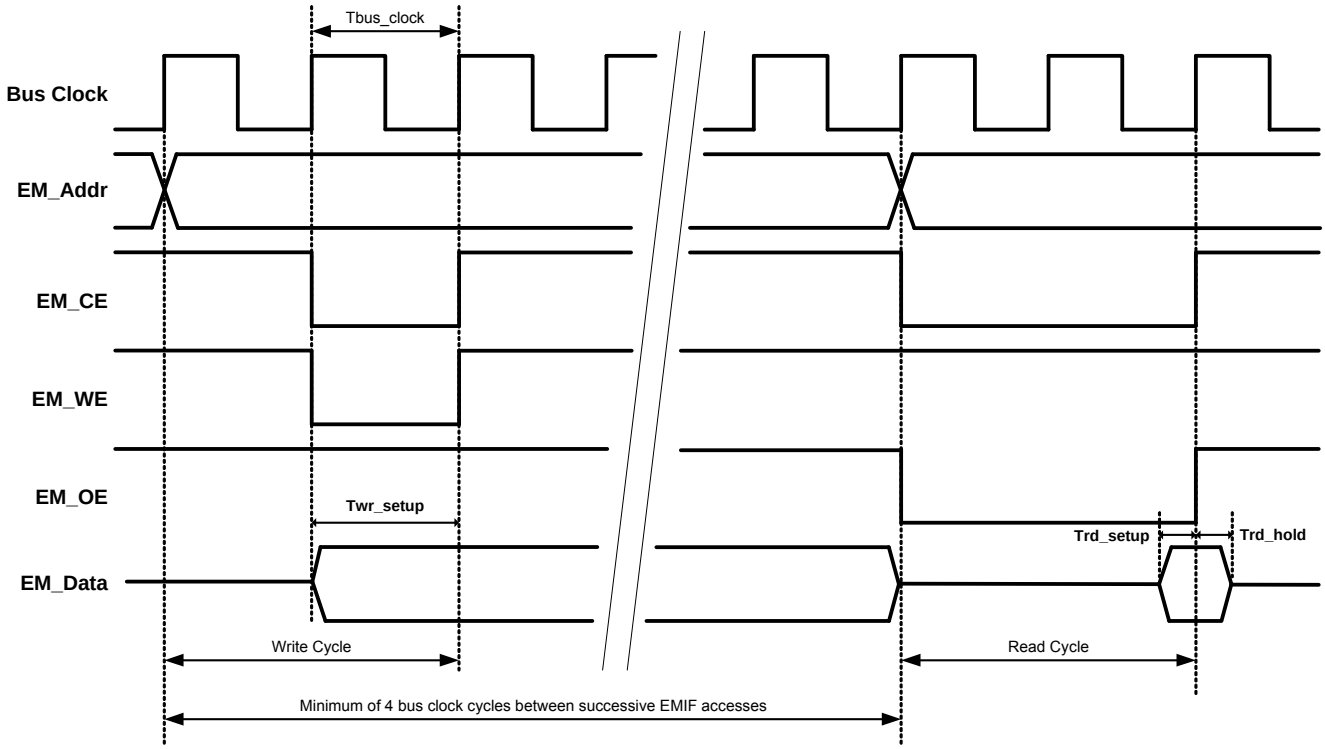


Table 11-53. Asynchronous Write and Read Timing Specifications[56]

Parameter	Description	Conditions	Min	Typ	Max	Units
Fbus_clock	Bus clock frequency[57]		–	–	33	MHz
Tbus_clock	Bus clock period[58]		30.3	–	–	ns
Twr_Setup	Time from EM_data valid to rising edge of EM_WE and EM_CE		Tbus_clock – 10	–	–	ns
Trd_setup	Time that EM_data must be valid before rising edge of EM_OE		5	–	–	ns
Trd_hold	Time that EM_data must be valid after rising edge of EM_OE		5	–	–	ns

Notes
56. Based on device characterization (Not production tested).
57. EMIF signal timings are limited by GPIO frequency limitations. See "GPIO" section on page 76.
58. EMIF output signals are generally synchronized to bus clock, so EMIF signal timings are dependent on bus clock frequency.

Figure 11-54. Synchronous Write and Read Cycle Timing, No Wait States

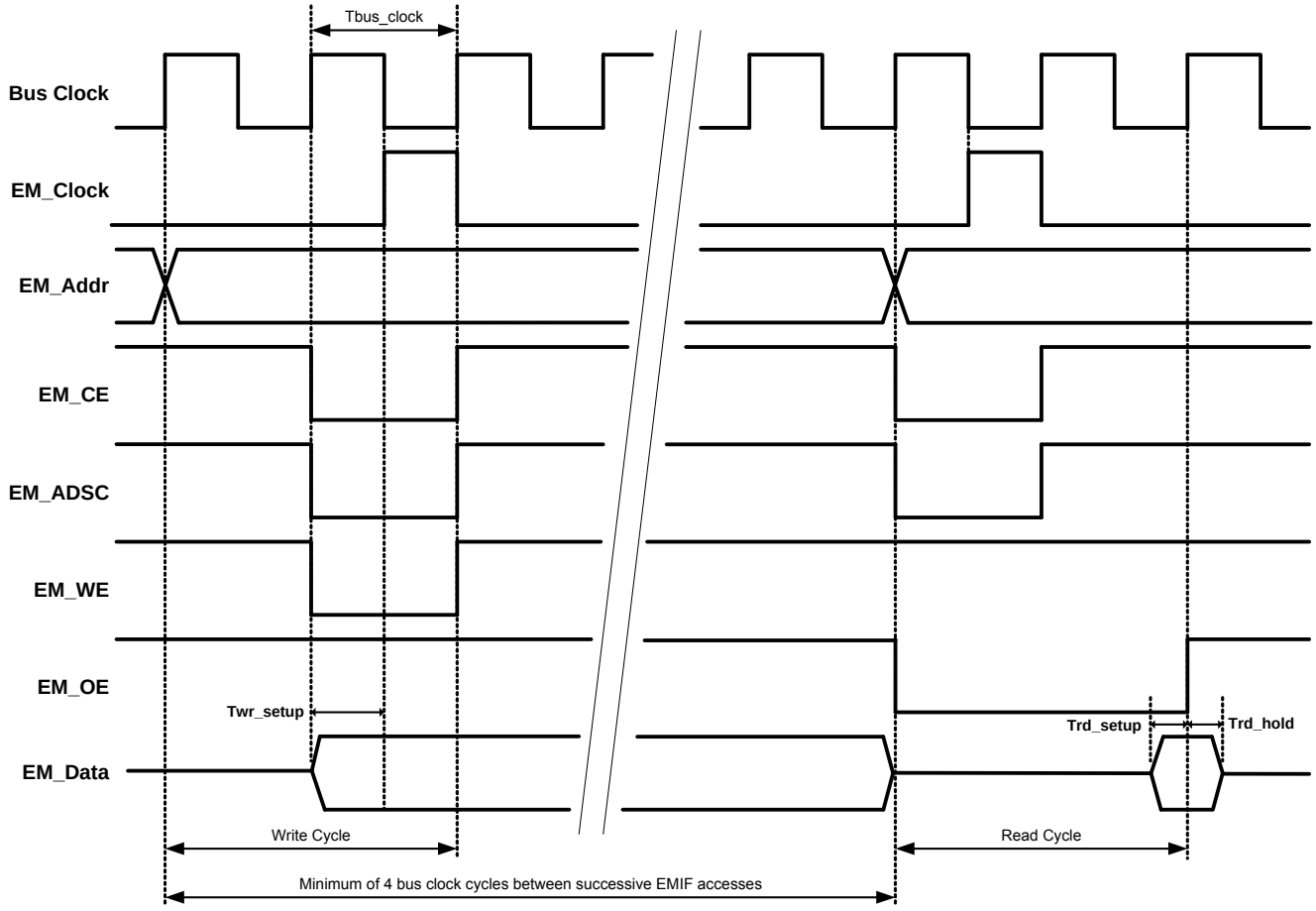


Table 11-54. Synchronous Write and Read Timing Specifications[59]

Parameter	Description	Conditions	Min	Typ	Max	Units
Fbus_clock	Bus clock frequency[60]		–	–	33	MHz
Tbus_clock	Bus clock period[61]		30.3	–	–	ns
Twr_Setup	Time from EM_data valid to rising edge of EM_Clock		Tbus_clock – 10	–	–	ns
Trd_setup	Time that EM_data must be valid before rising edge of EM_OE		5	–	–	ns
Trd_hold	Time that EM_data must be valid after rising edge of EM_OE		5	–	–	ns

Notes
59. Based on device characterization (Not production tested).
60. EMIF signal timings are limited by GPIO frequency limitations. See "GPIO" section on page 76.
61. EMIF output signals are generally synchronized to bus clock, so EMIF signal timings are dependent on bus clock frequency.

12. Ordering Information

In addition to the features listed in Table 12-1, every CY8C32 device includes: a precision on-chip voltage reference, precision oscillators, flash, ECC, DMA, a fixed function I²C, 4 KB trace RAM, JTAG/SWD programming and debug, external memory interface, and more. In addition to these features, the flexible UDBs and analog subsection support a wide range of peripherals. To assist you in selecting the ideal part, PSoC Creator makes a part recommendation after you choose the components required by your application. All CY8C32 derivatives incorporate device and flash security in user-selectable security levels; see the TRM for details.

Table 12-1. CY8C32 Family with Single Cycle 8051

Part Number	MCU Core				Analog								Digital				I/O[76]				Package	JTAG ID[77]
	CPU Speed (MHz)	Flash (KB)	SRAM (KB)	EEPROM (KB)	LCD Segment Drive	ADC	DAC	Comparator	SC/CT Analog Blocks	Opamps	DFB	CapSense	UDBs[75]	16-bit Timer/PWM	FS USB	CAN 2.0b	Total I/O	GPIO	SIO	USBIO		
16 KB Flash																						
CY8C3244AXI-153	50	16	2	0.5	✔	12-bit Del-Sig	1	2	0	0	–	✔	16	4	–	–	70	62	8	0	100-pin TQFP	0×1E099069
CY8C3244LTI-130	50	16	2	0.5	✔	12-bit Del-Sig	1	2	0	0	–	✔	16	4	–	–	46	38	8	0	68-pin QFN	0×1E082069
CY8C3244LTI-123	50	16	2	0.5	✔	12-bit Del-Sig	1	2	0	0	–	✔	16	4	–	–	29	25	4	0	48-pin QFN	0×1E07B069
CY8C3244PVI-133	50	16	2	0.5	✔	12-bit Del-Sig	1	2	0	0	–	✔	16	4	–	–	29	25	4	0	48-pin SSOP	0×1E085069
32 KB Flash																						
CY8C3245AXI-158	50	32	4	1	✔	12-bit Del-Sig	1	2	0	0	–	✔	20	4	–	–	70	62	8	0	100-pin TQFP	0×1E09E069
CY8C3245LTI-163	50	32	4	1	✔	12-bit Del-Sig	1	2	0	0	–	✔	20	4	–	–	46	38	8	0	68-pin QFN	0×1E0A3069
CY8C3245LTI-139	50	32	4	1	✔	12-bit Del-Sig	1	2	0	0	–	✔	20	4	–	–	29	25	4	0	48-pin QFN	0×1E08B069
CY8C3245PVI-134	50	32	4	1	✔	12-bit Del-Sig	1	2	0	0	–	✔	20	4	–	–	29	25	4	0	48-pin SSOP	0×1E086069
CY8C3245AXI-166	50	32	4	1	✔	12-bit Del-Sig	1	2	0	0	–	✔	20	4	✔	–	72	62	8	2	100-pin TQFP	0×1E0A6069
CY8C3245LTI-144	50	32	4	1	✔	12-bit Del-Sig	1	2	0	0	–	✔	20	4	✔	–	31	25	4	2	48-pin QFN	0×1E090069
CY8C3245PVI-150	50	32	4	1	✔	12-bit Del-Sig	1	2	0	0	–	✔	20	4	✔	–	31	25	4	2	48-pin SSOP	0×1E096069
CY8C3245FNI-212	50	32	4	1	✔	12-bit Del-Sig	1	2	0	0	–	✔	20	4	–	–	46	38	8	0	72-pin WLCSP	0x1E0D4069
64 KB Flash																						
CY8C3246LTI-149	50	64	8	2	✔	12-bit Del-Sig	1	2	0	0	–	✔	24	4	–	–	46	38	8	0	68-pin QFN	0×1E095069
CY8C3246PVI-147	50	64	8	2	✔	12-bit Del-Sig	1	2	0	0	–	✔	24	4	✔	–	31	25	4	2	48-pin SSOP	0×1E093069
CY8C3246AXI-131	50	64	8	2	✔	12-bit Del-Sig	1	2	0	0	–	✔	24	4	–	–	70	62	8	0	100-pin TQFP	0×1E083069
CY8C3246LTI-162	50	64	8	2	✔	12-bit Del-Sig	1	2	0	0	–	✔	24	4	–	–	29	25	4	0	48-pin QFN	0×1E0A2069
CY8C3246PVI-122	50	64	8	2	✔	12-bit Del-Sig	1	2	0	0	–	✔	24	4	–	–	29	25	4	0	48-pin SSOP	0×1E07A069
CY8C3246AXI-138	50	64	8	2	✔	12-bit Del-Sig	1	2	0	0	–	✔	24	4	✔	–	72	62	8	2	100-pin TQFP	0×1E08A069
CY8C3246LTI-128	50	64	8	2	✔	12-bit Del-Sig	1	2	0	0	–	✔	24	4	✔	–	48	38	8	2	68-pin QFN	0×1E080069
CY8C3246LTI-125	50	64	8	2	✔	12-bit Del-Sig	1	2	0	0	–	✔	24	4	✔	–	31	25	4	2	48-pin QFN	0×1E07D069
CY8C3246FNI-213	50	64	8	2	✔	12-bit Del-Sig	1	2	–	–	–	✔	24	4	–	–	46	38	8	–	72-pin WLCSP	0x1E0D5069

Notes

75. UDBs support a wide variety of functionality including SPI, LIN, UART, timer, counter, PWM, PRS, and others. Individual functions may use a fraction of a UDB or multiple UDBs. Multiple functions can share a single UDB. See the Example Peripherals on page 45 for more information on how UDBs can be used.
76. The I/O Count includes all types of digital I/O: GPIO, SIO, and the two USB I/O. See the I/O System and Routing on page 37 for details on the functionality of each of these types of I/O.
77. The JTAG ID has three major fields. The most significant nibble (left digit) is the version, followed by a 2 byte part number and a 3 nibble manufacturer ID.

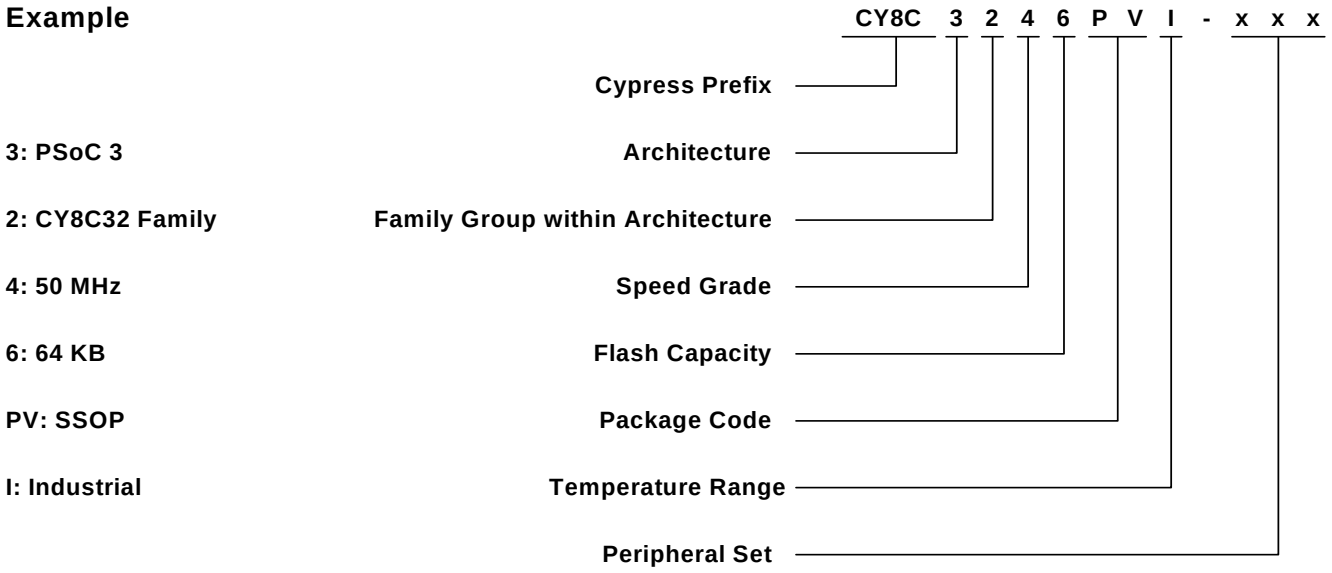
12.1 Part Numbering Conventions

PSoC 3 devices follow the part numbering convention described here. All fields are single character alphanumeric (0, 1, 2, …, 9, A, B, …, Z) unless stated otherwise.

CY8Cabcdefg-xxx

- a: Architecture
  - 3: PSoC 3
  - 5: PSoC 5
- b: Family group within architecture
  - 2: CY8C32 family
  - 4: CY8C34 family
  - 6: CY8C36 family
  - 8: CY8C38 family
- c: Speed grade
  - 4: 50 MHz
  - 6: 67 MHz
- d: Flash capacity
  - 4: 16 KB
  - 5: 32 KB
  - 6: 64 KB
- ef: Package code
  - Two character alphanumeric
  - AX: TQFP
  - LT: QFN
  - PV: SSOP
  - FN: CSP
- g: Temperature range
  - C: commercial
  - I: industrial
  - A: automotive
- xxx: Peripheral set
  - Three character numeric
  - No meaning is associated with these three characters.

Example



Tape and reel versions of these devices are available and are marked with a "T" at the end of the part number.

All devices in the PSoC 3 CY8C32 family comply to RoHS-6 specifications, demonstrating the commitment by Cypress to lead-free products. Lead (Pb) is an alloying element in solders that has resulted in environmental concerns due to potential toxicity. Cypress uses nickel-palladium-gold (NiPdAu) technology for the majority of leadframe-based packages.

A high level review of the Cypress Pb-free position is available on our website. Specific package information is also available. Package Material Declaration Datasheets (PMDDs) identify all substances contained within Cypress packages. PMDDs also confirm the absence of many banned substances. The information in the PMDDs will help Cypress customers plan for recycling or other “end of life” requirements.

14. Acronyms

Table 14-1. Acronyms Used in this Document

Acronym	Description
abus	analog local bus
ADC	analog-to-digital converter
AG	analog global
AHB	AMBA (advanced microcontroller bus architecture) high-performance bus, an ARM data transfer bus
ALU	arithmetic logic unit
AMUXBUS	analog multiplexer bus
API	application programming interface
APSR	application program status register
ARM®	advanced RISC machine, a CPU architecture
ATM	automatic thump mode
BW	bandwidth
CAN	Controller Area Network, a communications protocol
CMRR	common-mode rejection ratio
CPU	central processing unit
CRC	cyclic redundancy check, an error-checking protocol
DAC	digital-to-analog converter, see also IDAC, VDAC
DFB	digital filter block
DIO	digital input/output, GPIO with only digital capabilities, no analog. See GPIO.
DMA	direct memory access, see also TD
DNL	differential nonlinearity, see also INL
DNU	do not use
DR	port write data registers
DSI	digital system interconnect
DWT	data watchpoint and trace
ECC	error correcting code
ECO	external crystal oscillator
EEPROM	electrically erasable programmable read-only memory
EMI	electromagnetic interference
EMIF	external memory interface
EOC	end of conversion
EOF	end of frame
EPSR	execution program status register
ESD	electrostatic discharge
ETM	embedded trace macrocell

Table 14-1. Acronyms Used in this Document *(continued)*

Acronym	Description
FIR	finite impulse response, see also IIR
FPB	flash patch and breakpoint
FS	full-speed
GPIO	general-purpose input/output, applies to a PSoC pin
HVI	high-voltage interrupt, see also LVI, LVD
IC	integrated circuit
IDAC	current DAC, see also DAC, VDAC
IDE	integrated development environment
I^2C, or IIC	Inter-Integrated Circuit, a communications protocol
IIR	infinite impulse response, see also FIR
ILO	internal low-speed oscillator, see also IMO
IMO	internal main oscillator, see also ILO
INL	integral nonlinearity, see also DNL
I/O	input/output, see also GPIO, DIO, SIO, USBIO
IPOR	initial power-on reset
IPSR	interrupt program status register
IRQ	interrupt request
ITM	instrumentation trace macrocell
LCD	liquid crystal display
LIN	Local Interconnect Network, a communications protocol.
LR	link register
LUT	lookup table
LVD	low-voltage detect, see also LVI
LVI	low-voltage interrupt, see also HVI
LVTTL	low-voltage transistor-transistor logic
MAC	multiply-accumulate
MCU	microcontroller unit
MISO	master-in slave-out
NC	no connect
NMI	nonmaskable interrupt
NRZ	non-return-to-zero
NVIC	nested vectored interrupt controller
NVL	nonvolatile latch, see also WOL
opamp	operational amplifier
PAL	programmable array logic, see also PLD
PC	program counter
PCB	printed circuit board
PGA	programmable gain amplifier

Description Title: PSoC® 3: CY8C32 Family Data Sheet Programmable System-on-Chip (PSoC®) *(continued)* Document Number: 001-56955				
Revision	**ECN**	**Submission Date**	**Orig. of Change**	**Description of Change**
*M	3645908	06/14/2012	MKEA	Added paragraph clarifying that to achieve low hibernate current, you must limit the frequency of IO input signals. Revised description of IPOR and clarified PRES term. Changed footnote to state that all GPIO input voltages - not just analog voltages - must be less than Vddio. Updated 100-TQFP package drawing Clarified description of opamp Iout spec Changed “compliant with I2C” to “compatible with I2C” Updated 48-QFN package drawing Changed reset status register description text to clarify that not all reset sources are in the register Updated example PCB layout figure Removed text stating that FTW is a wakeup source Changed supply ramp rate spec from 1 V/ns to 0.066 V/µs Added “based on char” footnote to voltage monitors response time spec Changed analog global spec descriptions and values Added spec for ESDhbm for when Vssa and Vssd are separate Added a statement about support for JTAG programmers and file formats Changed comparator specs and conditions Added text describing flash cache, and updated related text Changed text and added figures describing Vddio source and sink Added a statement about support for JTAG programmers and file formats. Changed comparator specs and conditions Added text on adjustability of buzz frequency Updated terminology for “master” and “system” clock Deleted the text “debug operations are possible while the device is reset” Deleted and updated text regarding SIO performance under certain power ramp conditions Removed from boost mention of 22 µH inductors. This included deleting some graph figures. Changed DAC high and low speed/power mode descriptions and conditions Changed IMO startup time spec Added text on XRES and PRES re-arm times Added text about usage in externally regulated mode Updated package diagram spec 001-45616 to *D revision. Changed supply ramp rate spec from 1 V/ns to 0.066 V/µs Changed text describing SIO modes for overvoltage tolerance Added chip Idd specs for active and low-power modes, for multiple voltage, temperature and usage conditions Added chip Idd specs for active and low-power modes, for multiple voltage, temperature and usage conditions Updated del-sig ADC spec tables, to replace three the instances of “16 bit” with “12 bit”
*N	3648803	06/18/2012	WKA/ MKEA	No changes. EROS update.